

Exams for group S16-401

Wed, 16 Dec	08:30 — 10:05	TEST	Scientific Programs of Modern Times	🎓 Shmonin D.V.	📍 ДОТ	
Fri, 18 Dec	10:15 — 11:50	TEST	Innovative Approaches to Economics and Management	🎓 Medvedeva Y.M.	📍 ДОТ	
Tue, 22 Dec	12:45 — 14:20	TEST	Elect	Space and Television Systems	🎓 Krasnyuk A.A.	📍 ДОТ
Tue, 22 Dec	12:45 — 14:20	TEST	Elect	Radio frequency and microwave electronics	🎓 Bocharov Y.I.	📍 ДОТ
Tue, 22 Dec	14:30 — 16:05	TEST	Physical Principles of Nanoelectronics	🎓 Zebrev G.I.	📍 ДОТ	
Tue, 22 Dec	16:15 — 17:50	ATT	Elect	Micro and Nanotechnology Sensors	🎓 Podlepetskiy B.I.	📍 ДОТ
Tue, 22 Dec	16:15 — 17:50	ATT	Elect	Electronic Sensors	🎓 Sogoyan A.V.	📍 ДОТ
Wed, 23 Dec	11:55 — 13:30	TEST	Life Safety	🎓 Orlova K.N.	📍 ДОТ	
Wed, 23 Dec	16:15 — 17:50	ATT	Elect	Principles of functional and microwave microelectronics	🎓 Patrikeev L.N.	📍 ДОТ
Wed, 23 Dec	16:15 — 17:50	ATT	Elect	Electronic Systems Design	🎓 Boychenko D.V.	📍 ДОТ
Thu, 24 Dec	08:30 — 10:05	TEST	Scientific Research Work	🎓 Atkin E.V., Ulanova A.V., Yanenko A.V., Chumakov A.I., Chukov G.V., Savchenkov D.V., Nekrasov P.V., Krasnyuk A.A., Kondratenko S.V., Elesin V.V., Gromov D.V.	📍 ДОТ	
Fri, 25 Dec	12:45 — 14:20	ATT	Information and measurement systems in microelectronics	🎓 Belyakov V.V.	📍 ДОТ	
Fri, 25 Dec	16:15 — 17:50	TEST	Quantum Radiophysics	🎓 Larkin A.I.	📍 ДОТ	
Sat, 26 Dec	16:15 — 17:50	TEST	Opt	Effects of ionizing radiation from outer space on electronics	📍 ДОТ	
Sat, 26 Dec	17:55 — 19:30	TEST	Opt	Methods for evaluating and improving resistance of electronics to the effects of ionizing radiation from outer space	📍 ДОТ	
Mon, 28 Dec	10:15 — 12:40	ATT	Technology and Design of Electronic Equipment	🎓 Barbashov V.M.	📍 ДОТ	
Mon, 28 Dec	14:30 — 16:05	TEST	Principles of Optoelectronics	🎓 Voronov Y.A.	📍 ДОТ	
Wed, 13 Jan	09:00 — 13:00	EXAM	Technology and Design of Electronic Equipment	🎓 Barbashov V.M.	📍 ДОТ	
Mon, 18 Jan	09:00 — 13:00	EXAM	Elect	Principles of functional and microwave microelectronics	🎓 Patrikeev L.N.	📍 ДОТ
Mon, 18 Jan	09:00 — 13:00	EXAM	Elect	Electronic Systems Design	🎓 Boychenko D.V.	📍 ДОТ
Fri, 22 Jan	09:00 — 13:00	EXAM	Elect	Micro and Nanotechnology Sensors	🎓 Podlepetskiy B.I.	📍 ДОТ
Fri, 22 Jan	09:00 — 13:00	EXAM	Elect	Electronic Sensors	🎓 Sogoyan A.V.	📍 ДОТ
Tue, 26 Jan	09:00 — 13:00	EXAM	Information and measurement systems in microelectronics	🎓 Belyakov V.V.	📍 ДОТ	